

Dynamics of Photocarriers in Ga₂O₃-based Photocatalyst Studied by Transient Absorption Spectroscopy

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Ga₂O₃ is a wide bandgap material that is active for overall water splitting owing to its suitable band structures for H₂ and O₂ generation. By doping metal ions such as Zn²⁺ in Ga₂O₃, a remarkably high photocatalytic activity has been achieved with 71% quantum efficiency.¹ It is often believed that the introduction of dopants induces mid-gap states, which affect the optical absorption properties. Understanding the behavior of photogenerated electrons and holes is indispensable to determine the role of dopants in the enhancement of photocatalytic activity. Here, we investigated the dynamics of photocarriers in Ga₂O₃ and ZnGa₂O₄ powder photocatalysts. The effects of Ta and Nb doping on ZnGa₂O₄ were also examined. In order to study the dynamics of photocarriers, we performed transient absorption spectroscopy.²⁻³

In the experiments, each Ga₂O₃-based powder was excited by 266 nm laser pulses (0.04 mJ per pulse, 6-ns duration, 1 Hz).

We first examined the transient absorption spectra of Ga₂O₃ powder after 266 nm excitation. The spectra are shown in Figure 1A. We can observe two absorption features: negligible absorption at 9000 – 4000 cm⁻¹ and discernable absorption < 4000 cm⁻¹, which is monotonically increasing towards lower wavenumber. The spectral shape of the absorption at < 4000 cm⁻¹ is a characteristic of free electrons and/or shallowly trapped electrons.²⁻³ In the case of ZnGa₂O₄ (Fig. 1B), the spectra also show strong absorption < 4000 cm⁻¹; however, the absorption at 9000 – 4000 cm⁻¹ is clearly observable, which is absent in the absorption spectra of Ga₂O₃. Therefore, the absorption at 9000 – 4000 cm⁻¹ can be attributed to absorption of trapped electrons at

the defects induced by Zn incorporation in Ga₂O₃ producing ZnGa₂O₄.

The effect of Zn incorporation was further examined by observing the decay of free electrons probed at 2000 cm⁻¹ (Fig. 2). The decay of free electrons is faster in ZnGa₂O₄ than in Ga₂O₃. This result suggests that the defects in ZnGa₂O₄ play a key role to trap the electrons. However, when Nb is doped in ZnGa₂O₄, the number of surviving free electrons drastically increases, suggesting that Nb dopant is effective to produce long-lived free electrons. The detailed results will be presented at the symposium.

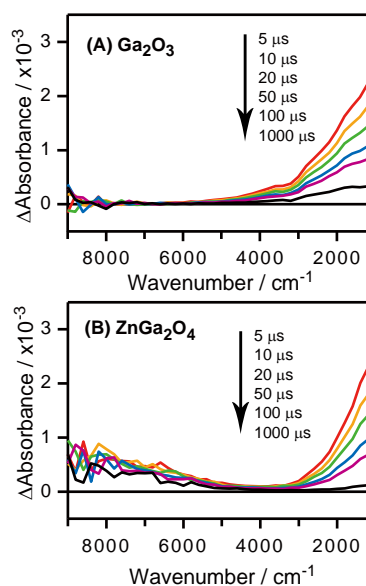


Fig.1 Transient absorption spectra of Ga₂O₃ (A) and ZnGa₂O₄ (B) powder photocatalysts.

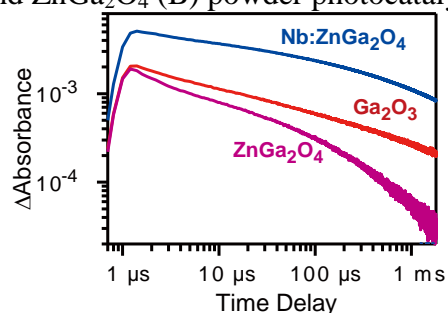


Fig. 2 Decay profiles of free electrons in Ga₂O₃, ZnGa₂O₄, and Nb-doped ZnGa₂O₄ probed at 2000 cm⁻¹ in a vacuum.

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